Reliability of NVM devices for I/O Acceleration on Supercomputing Systems

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Requirements for Next-gen I/O Subsystem

- TSUBAME2
 - Pioneer in the use of local flash storage
 - 200TB of SSDs for productive operation since 2010
 - Tired and hybrid storage environments, combining local flash with external Lustre FSs
- Industry Status
 - Various flash devices emerging
 - Available at reasonable cost
 - New Approaches
 - Flat Buffers
 - Burst Buffers etc.,



Issues for Introducing Flash Devices on Next-gen Supercomputers

• Flash Devices have various performance characteristics



- How much reliability of flash devices is required for burst buffers for next-gen supercomputers?
 - Maximize
 - Throughput, IOPS, Capacity, Reliability, etc.
 - Minimize
 - Cost for introducing flash devices on large-scale systems

Today's Talk

- Preliminary Evaluation of the endurance for SSD devices to support supercomputing I/O workloads
- Lustre I/O Monitoring for I/O workload analysis to evaluate the endurance

Towards Extreme-scale Supercomputing

- Memory/Storage Architecture
 - NVM(Non-Volatile Memory, Flash) is a key device for I/O subsystems
 - Capacity, Non-Volatility, Low energy consumption (vs. DRAM)
 - High throughput, Low latency, Low energy consumption (vs. HDD)
 - Various Flash Devices
 - Throughput:
 200MB/s ~ over 1GB/s
 - IOPS:
 10,000 ~ over 100,000
 - Interfaces : PCI-e attched, SATA3, mSATA, m.2, etc.



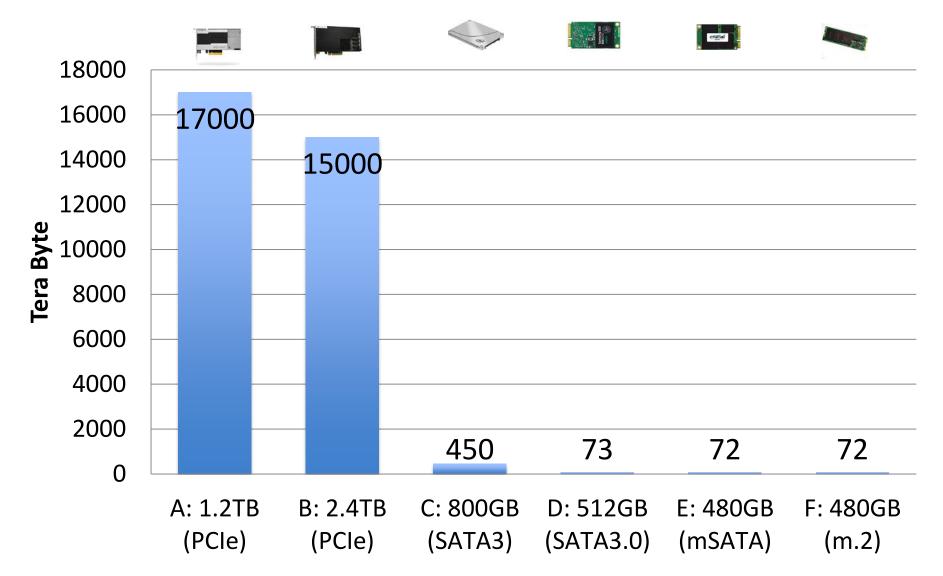
Reliability Evaluation of Flash Devices

- Power on Hours
 - Should support for operation duration
 - $-4 \sim 5$ years
- Endurance
 - Peta Byte Written (PBW), Tera Byte Written (TBW)
 - Deterioration Progress (%) = Total Write / PBW or TBW
- Average Erase Count (AEC)
 - Upper limit of erasure count (EC) is determined for a flash device
 - Deterioration Progress (%) = AEC / Upper Limit of EC
- Incidence of Bad Blocks
 - Impact for wear-leveling, GC

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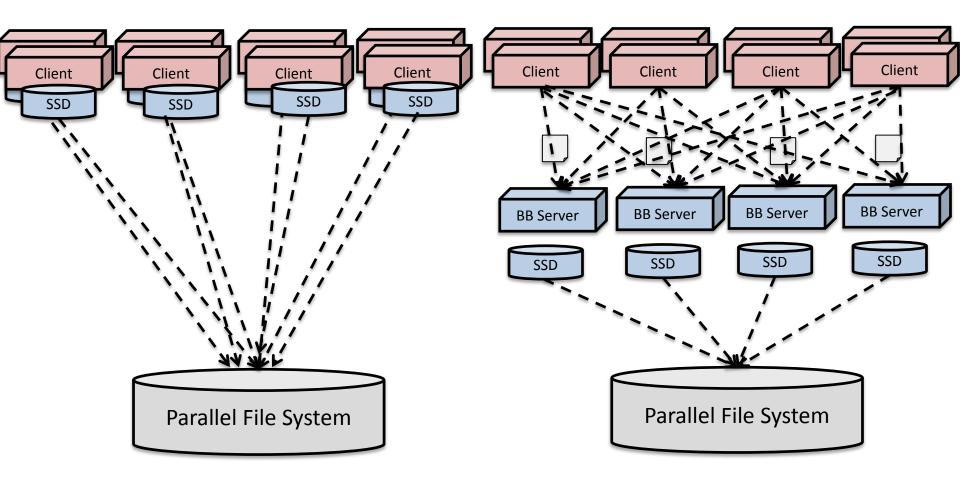
Endurance of Existing Flash Devices



SSD Configuration on Supercomputers

Flat Buffers (Node Local)

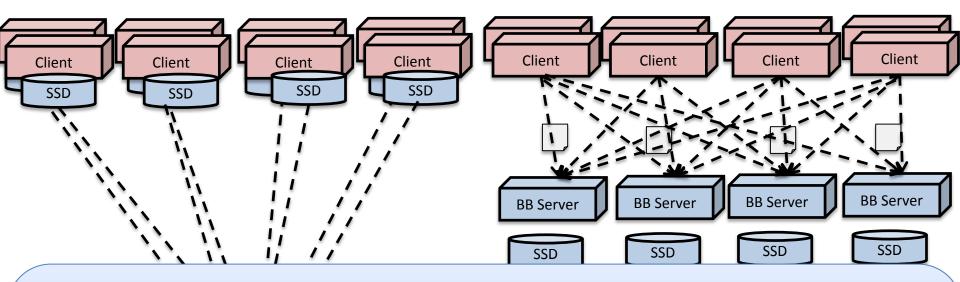
Burst Buffers (Intermediate Servers)



SSD Configuration on Supercomputers

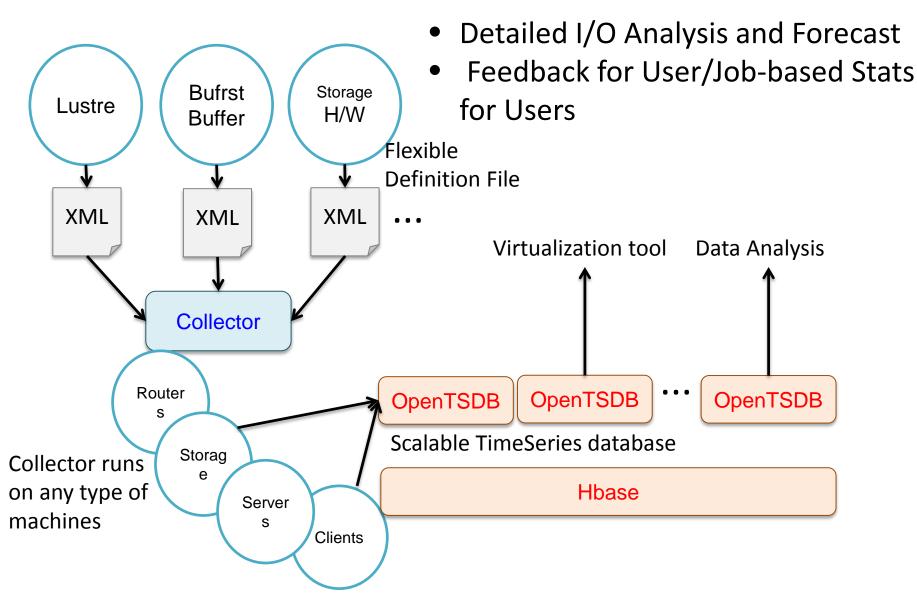


Burst Buffers (Intermediate Servers)



- How many SSD devices can we use to support the endurance of the volumes during the operation duration?
- We analyze the required endurance based on Lustre I/O monitoring

Lustre I/O Monitoring



Lustre I/O Monitoring

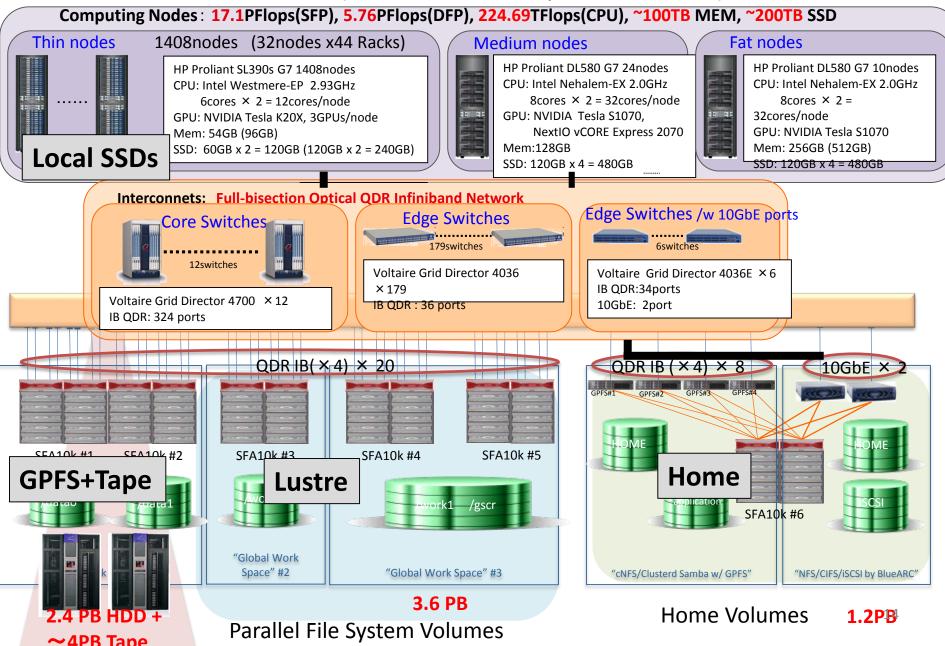
- Scalable and Flexible
 - Many Lustre stats, more than, 10M, 100M... stats
 - #OST * #client * stats * sampling
 - Future : #OST * #client * stats * JOBID(UID, etc) * sampling
 - Today, collected client's exported stats from Lustre servers
 - Lustre-2.1 is still running on server, no jobstats
 - Store data into scalable backend database
 - OpenTSDB and HBase
 - Selectable OpenSource frontend
 - All Lustre version support
 - /proc/fs/lustre structure changes on several lustre versions
 - A shadow definition XML of each version's /proc/fs/lustre

Endurance Evaluation

- Scheme
 - Estimate Total Write Size [PB] during operation years
 (1~5 years) based on Lustre Write Data Rate [GB/s]
 (Avg, Max)
 - Map the Total Write Size to aggregated SSD volumes
 - Evaluate the endurance of the aggregated SSD volumes based on the Total Write Size

TSUBAME2 System Overview

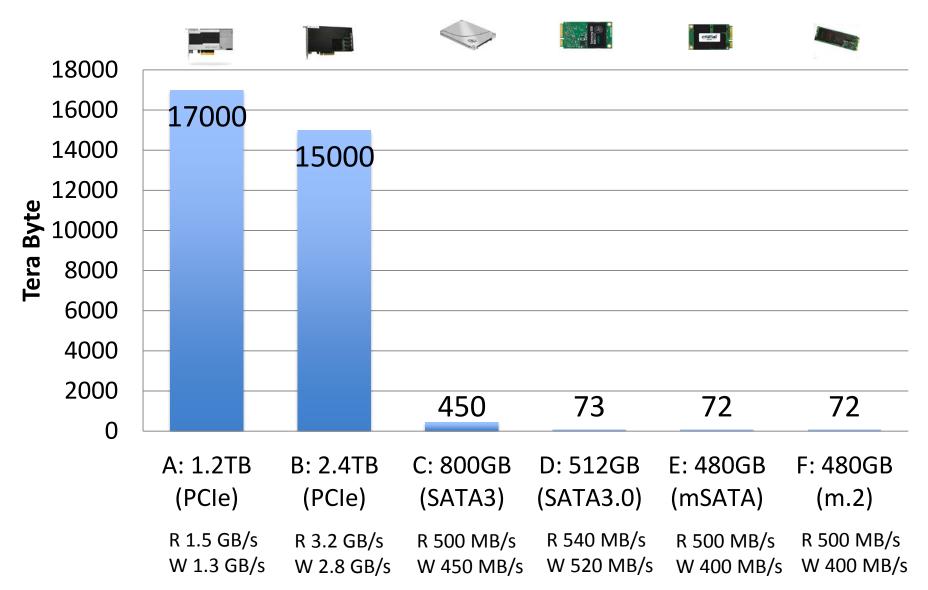
11PB (7PB HDD, 4PB Tape, 200TB SSD)



Configuration of SSD Volumes

- Configuration
 - Same as TSUBAME2
 - 2 devices per node * 1408 nodes = 2816 devices
- Assumption
 - Written Data are equally distributed to the aggregated SSD volumes
 - The endurance (TBW/PBW) of the aggregated SSD volumes is equal to the aggregation of the endurance of each SSD device

Target Devices

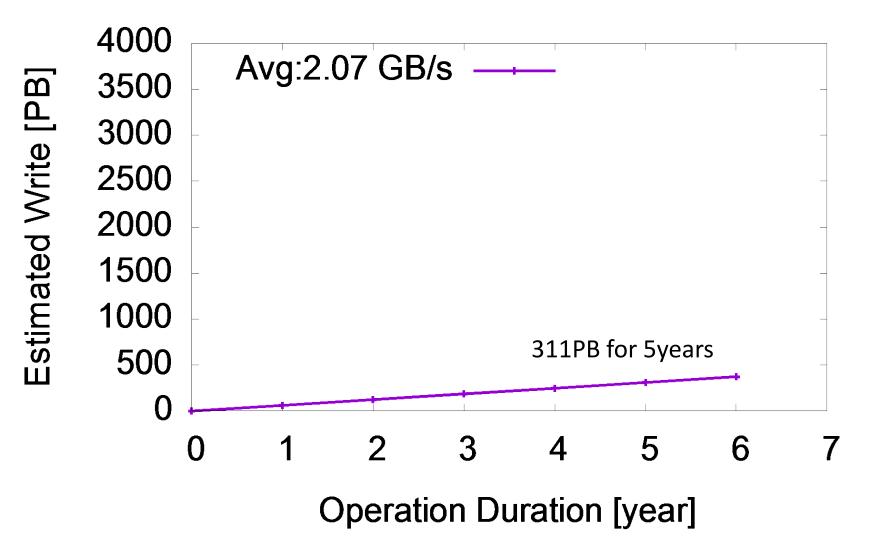


MAX 16.5 GB/s AVE 2.07 GB/s 2 Time [min]

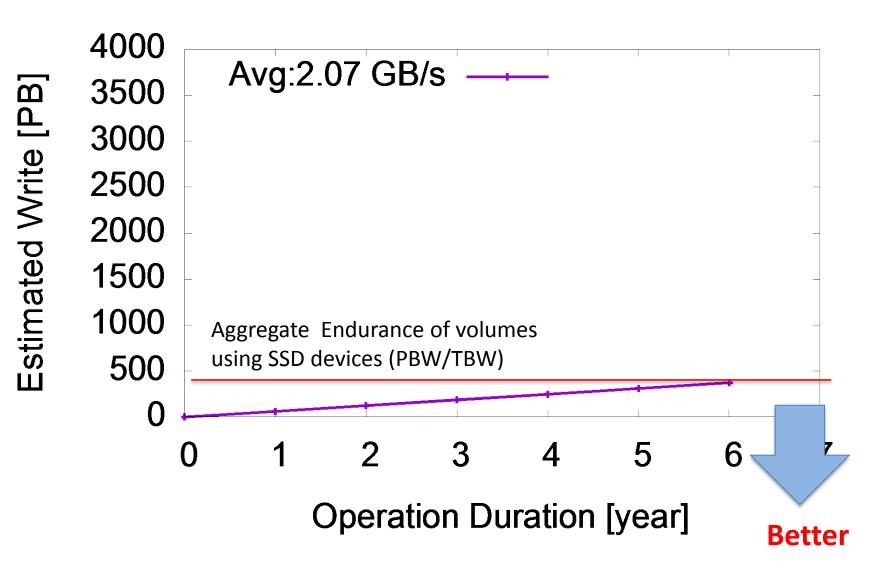
Data Rate [GB/s]

Aggregate Data Rate for TSUBAME2's Lustre Volumes

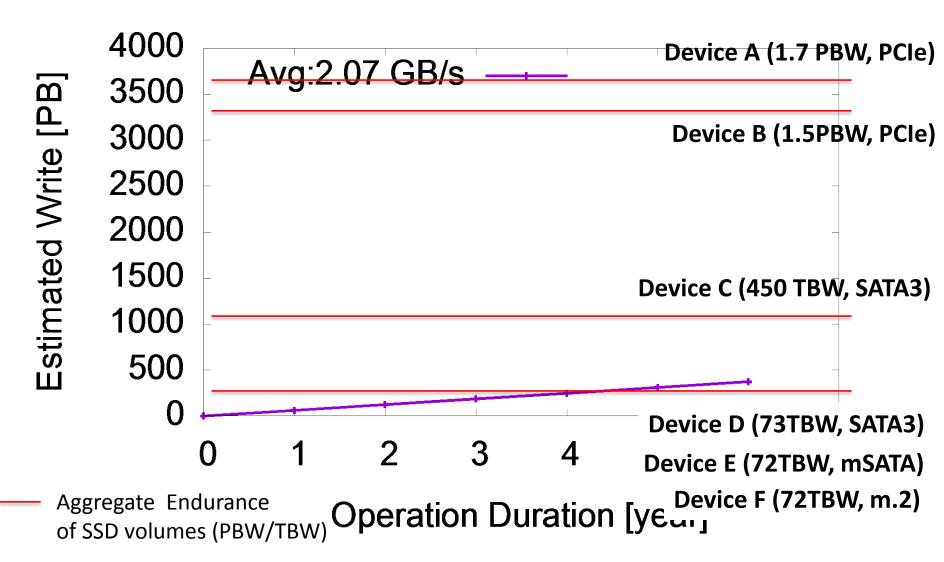
Estimated Write Based on Lustre I/O Workload on TSUBAME2



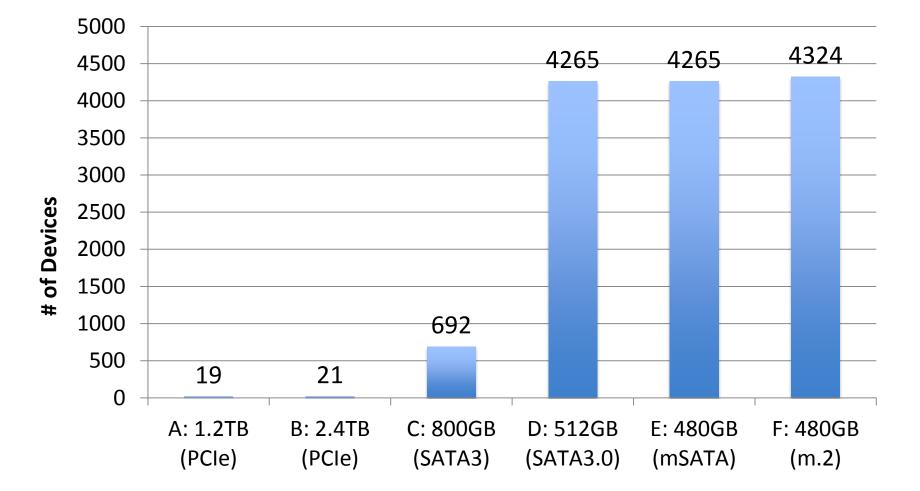
Endurance Based on TSUBAE2 SSD Configuration (Using 2816 devices)



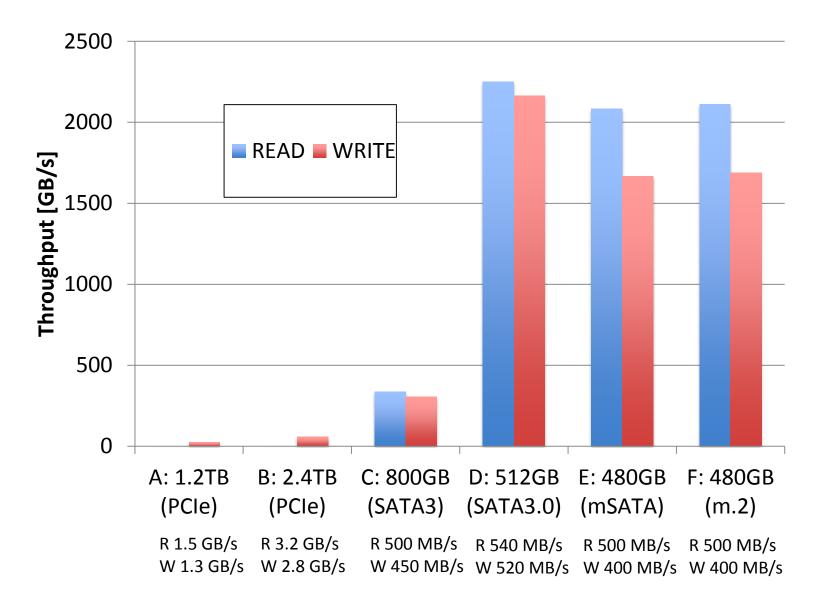
Endurance Based on TSUBAE2 SSD Configuration (Using 2816 devices)



of Required Devices to Support Estimated Total Write Size during Operation Duration (311PB for 5 years)



Aggregate Throughput



Discussion

- We can configure SSD-based buffer volumes using commodity-based SSD devices
 - Based on Lustre Write I/O workload
 - Several thousand of devices needed
- If we use high end SSD devices (PCI-e attached Flash), we can consolidate the SSD devices
 - Required Performance under the limited endurance of the SSD volumes
- Further evaluation by using more detailed I/O behavior is needed
 - Emulation of Burst Buffers etc.

Summary

- Preliminary Evaluation of Endurance for SSD devices to support supercomputing I/O workloads
 - Based on Lustre I/O monitoring

 High-performance Lustre I/O Monitoring for detailed I/O workload analysis